HVC-TO-017-1910

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 2KV (Include) to 5KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product is compliant with the RoHS & HF.)

2. Parts Number Code

С	1210	X	102	K	302	Т	0
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)

(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(5) Capacitance Tolerance

Code	Tolerance	Nominal Capacitance
K	± 10.0 %	More Than 10 pF

(2)Chip Size

Code	Length×Width	unit : mm(inch)
1210	3.20× 2.50) (.12× .10)

(6)Rated Voltage

Code	Rated Voltage (Vdc)
302	3,000

(3)Temperature Characteristics

X	X7R	-55°C~+125°C	± 15%
	Characteristic	Range	Coefficient
Code	Temperature	Temperature	Temperature

(7) Tapping

Code	Туре
Т	Tape & Reel

(4)Capacitance unit :pico farads(pF)

Code	Nominal Capacitance (pF)
102	1,000.0

^{※.} If there is a decimal point, it shall be expressed by an English capital letter R

(8) Special Requirement Code

	-
Code	Туре
0	Arc Prevention

3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolerance	Nominal Capacitance		
П	X7R	K (± 10.0 %)	E- 6 , E-12 series		

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0			2.2			4.7					
E- 6	1.	.0	1	.5	2	.2	3	.3	4.	.7	6.	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

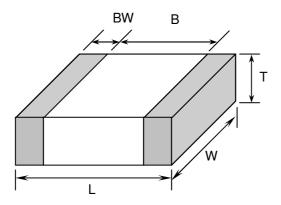
Class	Characteristic	Temperature Range	Reference Temp.		
П	X7R	-55℃ ~ +125℃	25℃		

5. Storage Condition

Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 12 months max.

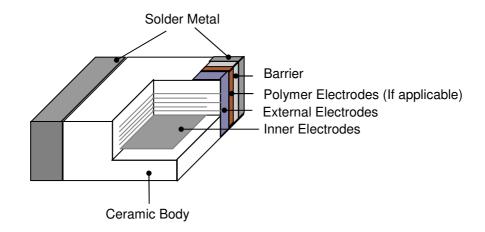
6. Dimensions

6.1 Configuration and Dimension:



					Unit:mm
TYPE	L	W	Т	B (min)	BW (min)
1210	3.20± 0.30	2.50± 0.20	1.25± 0.20	1.60	0.30

6.2 Termination Type:



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7. Performance

No.	Item	ı	;	Specifica	ation	Test Condition			
1	Visua	al	No abnormal exterior appearance			Visual inspection			
2	Dimens	sion	See Page 2			Visual inspecti	Visual inspection		
3	Insulati	ion	10,000M Ω m	iin.		Applied Voltage	e: 500V		
	Resista	nce				Charge time	: 60sec.		
4	Capacitance	Class	Within The Sp	ecified ⁻	Tolerance	Frequ	uency	Voltage	
		П				X7R	1KHz± 10%	1.0± 0.2Vrms	
5	Tan δ	Class	Char.		Maximum				
		П	X7R: 2.5% ma	ax.					
6	Withstan	iding	No dielectric	breakdo	own or	1000 < V ·120%	6 Rated Voltage		
	Voltag	ge	mechanical b	oreakdo	wn		up rate≦500v/s	.00	
						•	arge/discharge (
						than 50mA.	arge/discriarge v	Julient is less	
						triarr com, t.			
							voltage testing requi		
							solation fluid preven oltage over 1000Vdd		
						Criip Surface, at vi	ollage over 1000 val	<i>,</i> .	
_	Temperature	Class	Char. Temp. I	Rango	Cap. Change(%)	Class ∏ :			
7	Capacitance	I		+125°C	± 15%	(C2-C1)/C1	× 100%		
	Coefficient		X/II -33 C	<u> </u>	1 13/6	C1:Capacitance at standard temperature(25°C)			
	Goomoloni					C2: Capacitance at test temperature (T2)			
8	Adhesive S	trenath	No indication	of peelir	ng shall occur on	Pull force shall be applied for 10± 1 second.			
0	of Termin		the terminal e			≤ 06035N(,_	
	5 5					>060310N			
						<u> </u>	→ N·f		
	Resistance A	Innear-	No mechanics	al dama	ge shall occur.	Bending shall l	— be applied to the	1.0 mm with	
9		nce	i vo medianica	ıı uama(go silali occui.	_	ου αρρίισα το της	, i.o iiiiii willi	
	Flexure	Почико			1.0 mm/sec.	11 P 1. f			
	of C	C-Meter Capacitance Change		The duration of 5 ± 1sec	the applied force	es shall be			
	Substrate	Char. Cap. Change		0 ± 1860					
			X7R		≤ ± 12.5%		R230 ,	Danding	
								Bending Limit	
								T =	
						CW	eren		
						45±1mm	45±1mm		

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No.	Item			Specif	fication	Test Condition		
10	0 Solderability		More than 90% of the terminal surface is to be soldered newly, so metal part does not come out or dissolve.		ldered newly, so	Solder Temperature: 245± 5°C Dip Time: 5 ± 0.5 sec. Immersing Speed: 25±10% mm/s Solder: Lead Free Solder Flux: Rosin Preheat: At 80~120 °C for 10~30sec.		
11	Resistance Appear- To ance Soldering Capacit- Heat ance		occur.	nanical dai acteristic X7R	Cap. Change Within ± 7.5%	Class II capacitor shall be set for 48±4 hours at room temperature after one hour heat treatment at 150 +0/-10°C before initial measure. Preheat : At 150± 10°C For 60~120sec.		
		Tan δ Class II Insulation Resistance Withstand Voltage	To satisfy the specified initial value To satisfy the specified initial value To satisfy the specified initial value		ified initial value	Dip: Solder Temperature of 260±5°C Dip Time: 10 ± 1sec. Immersing Speed: 25±10% mm/s Flux: Rosin Measure at room temperature after cooling for Class II: 48 ± 4 Hours		
12	Tempera ture Cycle	Appearance Capacitance Tan δ Class II Insulation Resistance	occur Chara Class II To satisf	Characteristic Cap. Change a Class X7R Within ± 7.5%		Class II capacitor shall be set for 48± 4 hours room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30 2 25 3		
						3 Max Rated Temp. +3/-0 30 4 25 3 Measure at room temperature after cooling for Class II :48 ± 4 Hrs Solder the capacitor on P.C. Board shown in Fig 2. before testing.		

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No.	Ite	m		Speci	fication	Test Condition
13	Humidity	Appear- ance	No mechoccur	nanical dai	mage shall be	Class ☐ capacitor shall be set for 48± 4 hours at room temperature after one hour heat
		Capacit-	Chara	cteristic	Cap. Change	treatment at 150+0/-10 $^{\circ}\mathrm{C}$ before initial
		ance	Class	X7R	Within ± 15%	measure.
			П			Temperature : 40± 2°C
		Tan δ	Char		Maximum	Relative Humidity : 90 ~ 95%RH
		Class II	X7R: 5.0)% max		Test Time : 500 +12/-0Hr
		Insulation	1,000M	Ω min.		Current Applied : 50 mA Max.
		Resistance				Measure at room temperature after cooling for Class II : 48 ± 4Hrs
						Solder the capacitor on P.C. Board shown in Fig 2. before testing.
14	High	Appear-		nanical dai	mage shall be	Class ☐ capacitors applied DC voltage
		ance	occur			(following table) is applied for one hour at
	Load	Capacit-		cteristic	Cap. Change	_maximum operation temperature ±3°C then
		ance	Class II	X7R	Within ± 15%	shall be set for 48±4 hours at room temperature
		Tan δ	Char		 maximum	and the initial measurement shall be conducted.
		Class II	X7R: 5.0		IIIaxiiIIuIII	Voltage Conditioning :
		Insulation	1,000M			100% Rated Voltage meet MIL-PRF-49467(Group
		Resistance	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,			A/B)
						,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,
						Current Applied: 50 mA Max.
						Measure at room temperature after cooling for
						Class II: 48 ± 4 Hours
15	Vibration	Appear-		nanical dai	mage shall be	Solder the capacitor on P.C. Board shown in
		ance	occur	akadatta	0	Fig 2. before testing.
		Capacit-		cteristic	Cap. Change	Vibrate the capacitor with amplitude of 1.5mm
		ance	Class II	X7R	Within ± 7.5%	P-P changing the frequencies from 10Hz to
		Tan δ	To satisf	y the spec	ified initial value	55Hz and back to 10Hz in about 1 min.
		Class II		,	-	
		Insulation	To satisf	y the spec	rified initial value	Repeat this for 2 hours each in 3perpendicular
		Resistance		•		directions.

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Fig.1
P.C. Board for Bending Strength Test

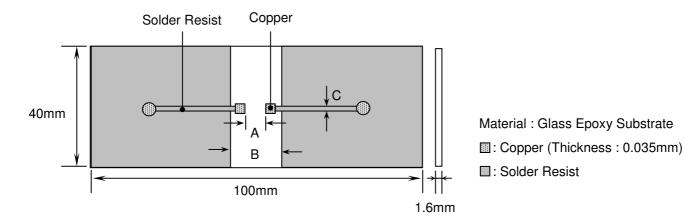
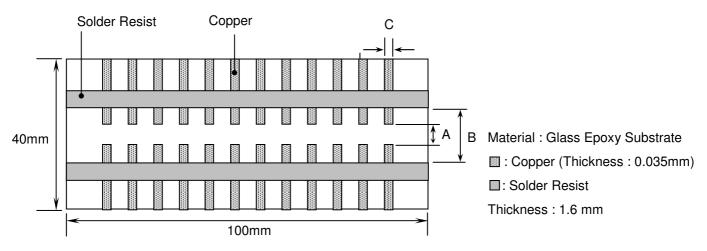


Fig.2
Test Substrate



Unit:mm

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Type	Α	В	С
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2211	4.5	8.0	3.0

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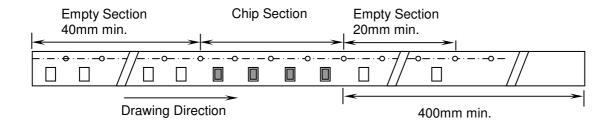


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0603/0805				
Material	T≦1.00mm	T>1.00mm			
Paper	4,000 pcs/Reel	NA			
Plastic	NA	3,000 pcs/Reel			

Tape	1206						
Material	T≦1.00mm	1.00mm < T ≤ 1.25mm	T>1.25mm				
Paper	4,000 pcs/Reel	NA	NA				
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel				

Tape			
Material	T≦1.25mm	1.25 mm $<$ T ≤ 2.40 mm	T>2.40mm
Paper	NA	NA	NA
Plastic	3,000 pcs/Reel	1,000/2,000 pcs/Reel	500/1,000 pcs/Reel

Tape	1812/2211/2220		1825/2	2208	
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1,000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1,000 pcs/Reel

NA: Not Available

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

 $5 g \cdot f \le Peel-Off Force \le 70 g \cdot f$

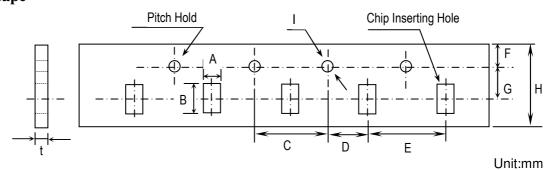
8.4.2 Measure Method



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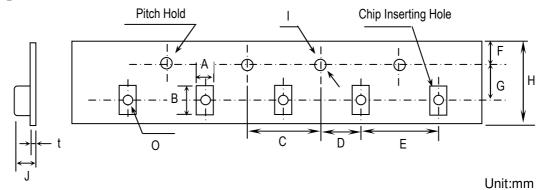
8.5 Paper Tape



	_	_			
1210	2.90± 0.20	3.6± 0.2			
1206	1.90± 0.20	3.5± 0.2			
0805	1.50± 0.20	2.3± 0.2			
0603	1.10± 0.20	1.9± 0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1
TYPE	Α	В	С	D	E

TYPE	F	G	Н		t
0603	1.75± 0.1	3.5± 0.05	8.0± 0.3	φ 1.5 +0.1/-0	1.1 max.
0805					
1206					
1210					

8.6 Plastic Tape



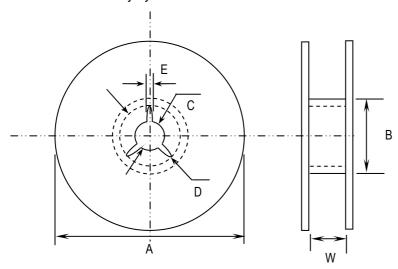
Туре	Α	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				

Туре	G	Н		J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.2 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		3.7 max.		1.5± 0.1
1812						
2208						
2211						
2220						

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8.7 Reel Dimensions

Reel Material: Polystyrene



Unit:mm

Туре	Α	В	С	D	Е	W
0603	178± 2.0	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0805						
1206						
1210						
1808						14± 0.15
1812						
2208						
2211						
2220						

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Precautionary Notes:

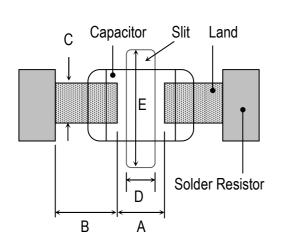
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

2.1 Size and recommend land dimensions for reflow soldering .

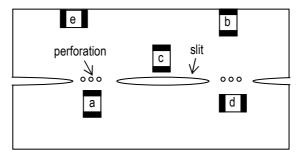


EIA Code Chip (mm		(mm)	Land (mm)					
EIA Code	L	W	Α	В	С	D	Е	
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4			
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		-	
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		-	
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		-	
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7	
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6	
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1	
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3	
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3	
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1	
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9	
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1	
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3	

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.

Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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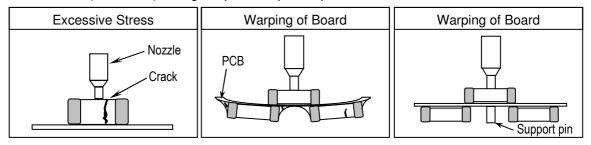


2.3 Layout Recommendation

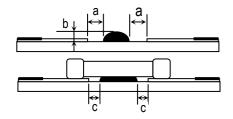
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Chip Solder Adhesive PCB Solder Land	Chassis Excessive Solder a	Solder Land
Recommendation	Chip Solder Resist Adhesive PCB Solder Land	Solder Resist $\alpha > \beta$	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example: 0805 & 1206				
a 0.2mm min.				
b	70 ~ 100 μm			
С	Do not touch the solder land			

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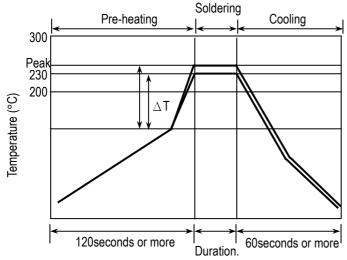
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4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at Peak Temperature.. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Peak Temp.($^{\circ}$ C) / Duration (sec)
1206 and Under	ΔT ≤ 100~130 max.
Pb-Sn Solder	250°C (max.) / 3sec(max.)
Lead Free Solder	260°C (max.) / 5sec(max.)

Recommended solder compositions

Sn-37Pb (Pb - Sn Solder)

Sn-3.0Ag-0.5Cu (Lead Free Solder)

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

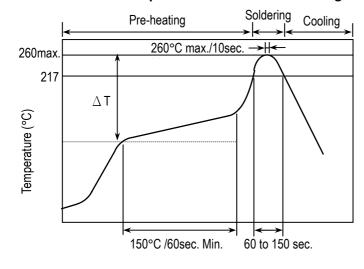
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3° C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (J-STD-020D)



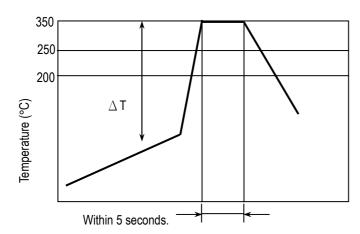
The cycles of soldering: Twice (max.)

Soldering Method	Change in Temp.(°C)
1206 and Under	∆ T ≦ 190 °C
1210 and Over	∆ T ≦ 130 °C

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4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 150 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

- 2) recommended solder iron condition
 - a.) Preheating Condition: Board and components should be preheated sufficiently at 150 ℃ or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350° C of value, and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - e.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic

body may cause thermal cracks.

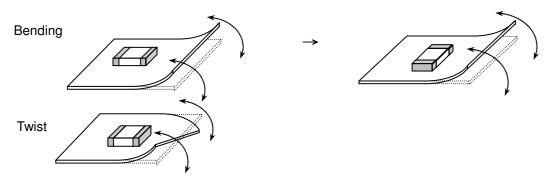
f.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

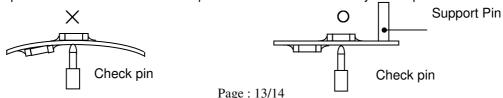
5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Higher potential of crack

Lower potential of crack



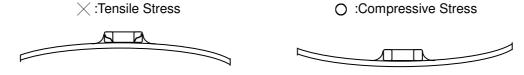
5.2 There is a potential of crack if board is warped due to excessive load by check pin



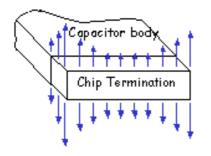


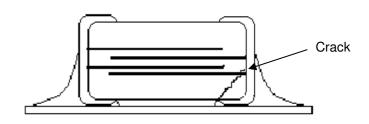
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- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis



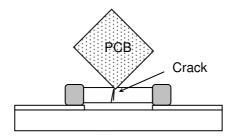


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

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单击下面可查看定价,库存,交付和生命周期等信息

>>Holy Stone(禾伸堂)